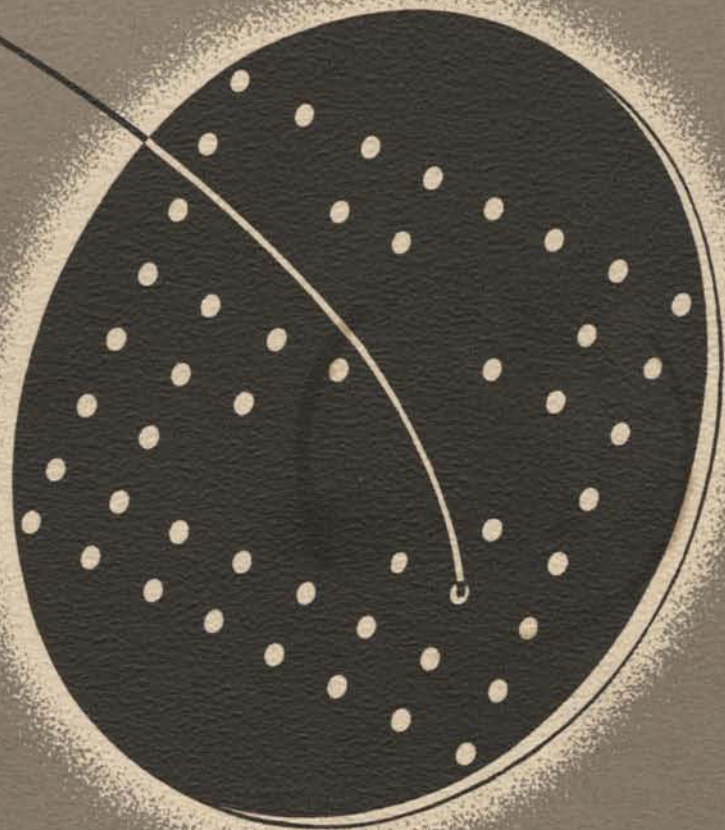
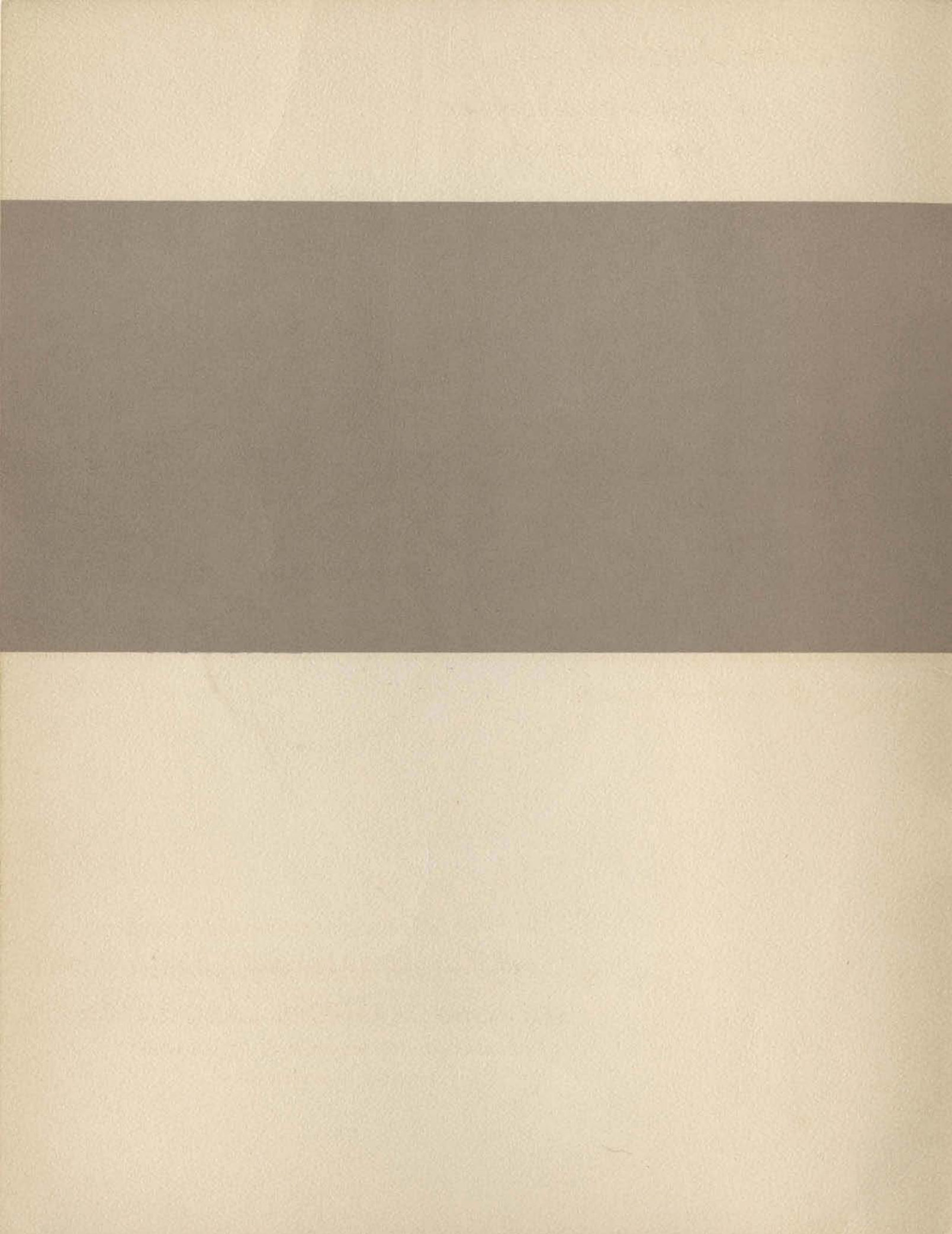


# Whirlwind 1



● ELECTRONIC COMPUTER DIVISION  
**SERVOMECHANISMS LABORATORY**  
MASSACHUSETTS INSTITUTE OF TECHNOLOGY



























# Summary of Whirlwind 1 Specifications

TYPE OF COMPUTER . . . . .	General purpose, high-speed
DESIGN . . . . .	Electronic, digital
NUMBER SYSTEM USED . . . . .	Binary
REGISTER LENGTH (basic) . . . . .	16 Binary digits
METHOD of HANDLING NUMBERS . . . . .	Parallel digit transmission, addition, and storage
TYPE of INTERNAL STORAGE . . . . .	Electrostatic storage tubes
CAPACITY of INTERNAL STORAGE . . . . .	Initially 256 registers; when complete, 2048 registers
ACCESS TIME to INTERNAL STORAGE . . . . .	Initially 25 microseconds; when complete, 6 microseconds
BASIC FUNCTIONAL DESIGN . . . . .	0.1-microsecond pulses, representing in- structions or numbers, are distributed via gate tubes, which pass pulses only when a coincidence signal from a memory device, such as a flip-flop, is present
PULSE REPETITION FREQUENCY . . . . .	2 megacycles in arithmetic element, 1 megacycle elsewhere
ADDITION TIME (in microseconds)	
To add two numbers already in the arithmetic element . . . . .	2
To get one number from storage and add it to one already in the arithmetic element . . . . .	Initially 60, goal . . . . 24
To get two numbers from storage, add them, and to transfer the answer to storage . . . . .	Initially 180, goal . . . . 72
AVERAGE MULTIPLICATION TIME, INCLUDING ROUNDOFF (in microseconds)	
To multiply two numbers already in the arithmetic element . . . . .	20
To get one number from storage and multiply it by one already in the arithmetic element . . . .	Initially 75, goal . . . . 39
To get two numbers from storage, multiply them, and to transfer the product to storage . . .	Initially 195, goal . . . . 87
INPUT AND OUTPUT . . . . .	Typewriter, perforated paper tape, magnetic tape, magnetic drum, oscilloscope display
ERROR DETECTION . . . . .	By built-in identity checks and miscellaneous alarms
TROUBLE LOCATION . . . . .	By automatic marginal-checking system which locates deteriorating components during test periods

